

BayesFLo: Bayesian fault localization of complex software systems

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Abstract

Software testing is essential for the reliable development of complex software systems. A key step in software testing is fault localization, which uses test data to pinpoint failure-inducing combinations for further diagnosis. Existing fault localization methods, however, are largely deterministic, and thus do not provide a principled approach for assessing probabilistic risk of potential root causes, or for integrating domain and/or structural knowledge from test engineers. To address this, we propose a novel Bayesian fault localization framework called BayesFLo, which leverages a flexible Bayesian model on potential root cause combinations. A key feature of BayesFLo is its integration of the principles of combination hierarchy and heredity, which capture the structured nature of failure-inducing combinations. A critical challenge, however, is the sheer number of potential root cause scenarios to consider, which renders the computation of posterior root cause probabilities infeasible even for small software systems. We thus develop new algorithms for efficient computation of such probabilities, leveraging recent tools from integer programming and graph representations. We then demonstrate the effectiveness of BayesFLo over state-of-the-art fault localization methods, in a suite of numerical experiments and in two motivating case studies on the JMP `XGBoost` interface.

Keywords: Bayesian modeling, Combinatorial testing, Fault localization, Software testing

1 Introduction

Software testing – the process of executing a program with the intent of finding errors (Myers et al., 2004) – is an essential step in the development of robust software applications. Such testing aims to reveal (and subsequently fix) as many bugs as possible prior to the release of a software application, thus greatly reducing the likelihood of encountering failures for the end-user. This is crucial in an era where nearly all facets of daily life involve human interaction with software applications. There are, however, two critical challenges. First, each software test can be *time-consuming* to perform. This involves not only running the software application itself, which can be intensive in an era of complex machine learning models with massive data, but also determining whether the software deviates from its expected behavior. The latter, known as the “oracle problem” (Barr et al., 2014), typically requires an independent assessment of numerical accuracy of software outputs (Lekivetz and Morgan, 2021), which can be very costly. Second, the number of test cases required for thorough software examination can easily be overwhelming. As “bugs [tend to] lurk in corners and congregate at boundaries” (Beizer, 2003), software testing typically focuses on boundary values and the *combinations* of inputs, which can grow rapidly. For practical applications, it is thus wholly infeasible to exhaustively test all input combinations (Kumar, 2019), which can easily require *billions* of test cases!

These two fundamental challenges open up a world of exciting new statistical directions for this application of rising importance. Such directions can roughly be categorized into two topics. The first is a careful *design* of test cases to perform, with the joint goals of identifying failure settings and diagnosing its underlying root causes. Statistically, this can be viewed as an *experimental design* problem for software fault diagnosis. There has been notable work on this front. An early approach is the one-factor-at-a-time design (Frey et al., 2003; Wu and Hamada, 2009), which varies inputs sequentially one at a time; this is suitable for unit testing (Runeson, 2006), which focuses on investigating *individual* inputs. Another approach is pairwise testing (Bach and Schroeder, 2004), which examines all *pairwise* combinations of inputs; test case generation for this setting has been explored in Tai and Lei (2002). A more general approach is *combinatorial testing* (Nie and Leung, 2011b), which investigates combinations involving more than two inputs. For combinatorial testing, the design of choice is a *covering array* (CA; Colbourn, 2004); such designs aim to

represent (or “cover”) each combination of inputs (up to a specified order) at least once in the test runs (Dalal and Mallows, 1998). CAs are thus ideal for detecting failures from limited test runs; we will discuss CAs in greater detail later in Section 2.

With the initial test cases conducted and failures detected, the second direction is *fault localization* (Wong et al., 2023): the use of this test data to pinpoint root causes. This is a highly challenging problem due to the overwhelming number of scenarios to consider for potential root causes. To see why, consider a software application for training boosted tree models, and suppose it has $I = 10$ input factors each with two levels. Such levels could represent, e.g., low / high learning rate or low / high tree depth. There are thus a total of $\sum_{i=1}^{10} \binom{10}{i} 2^i = 59048$ input combinations, e.g., the combination of low learning rate with high tree depth, that might be potential root causes. Since each combination is either a root cause or not, this results in a whopping 2^{59048} different scenarios to consider for potential root causes! Fault localization then requires gauging which of these many scenarios is likely given test set outcomes, which is clearly a computationally intensive task (Wong et al., 2023), even for systems with a moderate number of inputs I and few failed test cases.

Due to this sheer amount of potential root causes, researchers have developed *deterministic* (i.e., non-probabilistic) fault localization techniques that, based on the outcomes of initial test cases, select a handful of suspicious input combinations for further investigation. This includes the work of Nie and Leung (2011a), which proposed a minimal failure-causing schema and used it to narrow down the search range for potential root causes and to guide subsequent test case generation. Niu et al. (2013) proposed a notion of tuple relationship tree for visualizing the relationships among all input combinations. Such a tree is utilized to eliminate “healthy” combinations and to propose subsequent test cases for further examination of the system. More recently, Ghandehari (2016) and Ghandehari et al. (2018) introduced a two-phase approach for finding faulty statements in a software system. Such approaches have been integrated, either in full or in part, within the Covering Array Analysis module in the statistical software package JMP (henceforth called JMP; Jones and Sall, 2011).

Despite the above body of work, a key weakness of such existing methods is that they are not *probabilistic* in nature. These methods thus provide little insight on the *probability* of a combination being a root cause given test outcomes. Such probabilities are critical for

confident fault localization; they (i) provide a principled statistical approach for assessing root cause risks, and thus a principled measure of *confidence* that an identified suspicious combination is (or is not) a root cause. One way to achieve this is via a Bayesian modeling approach, where prior root cause probabilities are assigned on each input combination, then updated by conditioning on the observed test set results. Such a Bayesian framework, when carefully elicited and specified, offers three further advantages over the state-of-the-art. It (ii) gives a flexible framework for integrating prior *structural* knowledge on root cause behavior that are known to be present, which permits quicker fault localization with fewer tests. By integrating such structure, a Bayesian approach may also (iii) provide a more informed *ranking* of potential root causes, by *disentangling* the many potential effects returned by existing methods, which are often too numerous to fully explore in practice. Finally, a Bayesian approach can (iv) naturally incorporate prior *domain knowledge* from test engineers (Lekivetz and Morgan, 2018), which can further accelerate fault localization. We will demonstrate such advantages in later case studies.

We thus propose a new Bayesian Fault LOcalization (BayesFLo) framework, which addresses the aforementioned limitations via the four advantages (i)-(iv). The main workhorse of BayesFLo is a new probabilistic model on root cause indicators over all possible input combinations. This model carefully embeds the desirable principles of combination hierarchy and heredity (Lekivetz and Morgan, 2021), which capture the structured nature by which software root causes arise. We show that the integration of such principles, which are derived from the well-known principles of effect hierarchy and heredity (Wu and Hamada, 2009) for analyzing experimental data, can improve the identification of root causes from limited test cases. A critical challenge for Bayesian computation is the sheer number of considered combinations; without careful manipulation, this renders the computation of posterior root cause probabilities to be wholly infeasible. We thus develop a new algorithmic framework for efficient computation of such posterior probabilities, leveraging recent tools from integer programming and graph representations. We then demonstrate the practical advantages of BayesFLo over the state-of-the-art, in a suite of numerical experiments and our motivating application on fault localization for JMP’s interface of `XGBoost`, an open-source machine learning library for scalable tree boosting (Chen and Guestrin, 2016).

The paper is organized as follows. Section 2 outlines our motivating application on fault localization of the JMP `XGBoost` interface, as well as limitations of the current state-of-

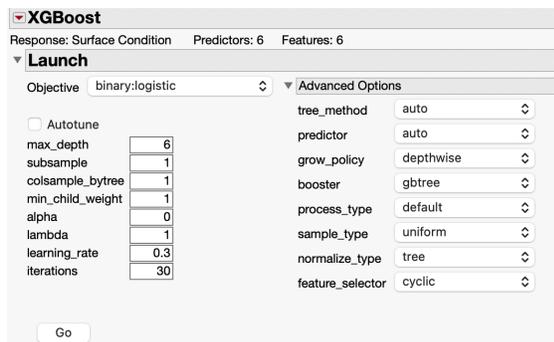


Figure 1: The user interface for the XGBoost library in JMP Pro 17.0.

JMP XGBoost Case Study 2		
Hyperparameter	Level 1	Level 2
max_depth	6	9
alpha	0	1
lambda	0	1
learning_rate	0.05	0.3
booster	gbtree	dart
sample_type	uniform	weighted
normalize_type	tree	forest

Table 1: Considered hyperparameters (factors) for our motivating XGBoost case study.

the-art. Section 3 presents the BayesFLo model, and describes the combination hierarchy and heredity principles embedded in its prior specification. Section 4 proposes novel algorithms for computing the desired posterior root cause probabilities of potential root cause combinations. Section 5 investigates the effectiveness of BayesFLo over the state-of-the-art in a suite of numerical experiments. Section 6 then explores the application of BayesFLo in two practical case studies on fault localization of the JMP XGBoost interface. Section 7 concludes the paper.

2 Motivating Application: Fault Localization of XGBoost

2.1 Background & Challenges

Our motivating application is the fault localization for JMP’s interface of the XGBoost library (Chen et al., 2015; Chen and Guestrin, 2016). XGBoost, short for “eXtreme Gradient Boosting”, is a popular machine learning software package, which provides an efficient and scalable implementation of gradient boosting (see, e.g., Friedman, 2002). This library is widely used in the statistical and machine learning communities, and has gained widespread popularity in broad applications, including epidemiology (Ogunleye and Wang, 2019) and e-commerce (Song and Liu, 2020). The popularity of XGBoost can be attributed to several reasons: it offers an algorithmic optimization framework with built-in parallel and distributed computing capabilities, and is available as an open-source library in many coding environments, including Python, R, C++ and Julia. We focus in this work on its implementation within JMP (Jones and Sall, 2011), a subsidiary of SAS Institute focused on statistical analysis for scientists and engineers.

A critical challenge for a robust implementation of **XGBoost** (and indeed, of most machine learning software) is the verification of software performance over a broad range of hyperparameter settings. This verification is particularly important given the increasing dependence of modern machine learning algorithms on a careful tuning of hyperparameter settings. Figure 1 shows the **XGBoost** User Interface in JMP Pro Version 17.0. We see that there are many hyperparameters that users may freely vary for model training. With this flexibility, however, the verification of this software via a brute-force testing of *all* hyperparameter combinations is wholly infeasible. One solution is to first (i) construct and run the software system on a designed test set of hyperparameter settings. Upon encountering failures, one then (ii) identifies potential root causes for further investigation, namely, fault localization.

Consider first step (i) for our **XGBoost** case study with $I = 7$ two-level factors; we return to this case study later in Section 6.2. Table 1 summarizes the considered factors and its levels. A popular test set design is a *covering array* (CA; Colbourn, 2004; Lekivetz and Morgan, 2021), which is defined as follows. Take a matrix with dimensions $M \times I$, and suppose its i -th column takes J_i distinct levels for some integer $J_i \geq 2$. Then this array is a CA of strength s , if within any choice of s columns, each possible level combination involving these columns occurs at least once. For software testing, this CA can be used to design a test set with M runs and I inputs (where the i -th input has J_i levels); the levels in its m -th row then specify the input settings for performing the m -th test run. Table 2 (left) shows a strength-3 CA for the **XGBoost** case study. This CA achieves the desired coverage condition with a minimal number of $M = 12$ runs, thus greatly reducing the number of runs on the expensive software system. Note that, with this strength-3 CA, all two- and three-factor input combinations are investigated in at least one test run; if one of these combinations causes an error, we would observe a corresponding failure in a test run.

Step (ii) then aims to pinpoint potential root causes from the test runs. This is the key problem explored in this work, and is highly challenging for several reasons. Table 2 (right) shows the test outcomes for our case study, where 0 indicates a passed case and 1 a failed one. Here, there are a total of $\sum_{i=1}^7 \binom{7}{i} 2^i = 2186$ input combinations, e.g., `max_depth = 9` and `alpha = 0`, that may be potential root causes. Since each combination is either a root cause or not, there are thus a whopping 2^{2186} different root cause scenarios to consider for fault diagnosis. A key challenge is the parsing of these many scenarios to

Test Cases & Outcomes for JMP XGBoost Case Study 2							
max_depth	alpha	lambda	learning_rate	booster	sample_type	normalize_type	Outcome
9	0	0	0.05	gbtree	weighted	forest	1
9	0	1	0.3	dart	weighted	tree	0
6	1	0	0.3	gbtree	uniform	tree	0
6	1	0	0.05	dart	weighted	forest	0
9	1	1	0.3	gbtree	weighted	forest	1
6	0	1	0.3	dart	uniform	forest	0
6	1	1	0.05	dart	weighted	tree	0
6	0	0	0.3	gbtree	weighted	tree	1
6	0	1	0.05	gbtree	uniform	forest	1
9	1	1	0.05	gbtree	uniform	tree	0
9	0	0	0.05	dart	uniform	tree	0
9	1	0	0.3	dart	uniform	forest	0

Table 2: The $M = 12$ -run test design and corresponding test outcomes for our motivating XGBoost case study. Here, an outcome of 0 indicates a passed test case and 1 indicates a failed one.

find which are likely given the observed test set, then how to use this analysis for efficient system diagnosis. Another challenge is the need for assessing *confidence* that an identified suspicious combination is indeed a root cause. This provides test engineers a principled way for deciding which combinations are likely root causes and need to be investigated in subsequent tests, and which are likely not root causes and can be safely ignored; such uncertainty estimation is thus critical for trustworthy fault diagnosis (Zhou et al., 2023).

2.2 State-of-the-Art and Its Limitations

Existing fault localization methods, as described earlier, are largely deterministic in nature. This includes the work of Niu et al. (2013), who used a tuple relationship tree to capture relationships among all factor combinations based on testing results. For a given test case, this tree lists all considered combinations (tuples) along the branches of the tree, which can then be used to classify which class (faulty or healthy) each tuple belongs to. Nie and Leung (2011a) introduced the idea of a minimal failure-causing schema, defined as the smallest-order factor combination such that all test cases containing them trigger a failure. This schema is then applied for guiding fault localization and subsequent testing. Ghandehari (2016) and Ghandehari et al. (2018) developed a two-stage combinatorial-testing-based fault localization approach. The key idea is to identify potential failure-inducing factor combinations from test results by eliminating combinations that appear in passed test cases, then rank such combinations based on two proposed “combination suspiciousness” and “environment suspiciousness” metrics. Lekivetz and Morgan (2018)

proposed a deterministic ranking procedure that incorporates a domain-knowledge-guided weighting scheme. A key limitation of such methods is that they are not probabilistic in nature, and thus do not provide the desired probabilistic measure of confidence for how *likely* a particular combination is a root cause. The above methods also unfortunately do not have publicly-available code; we instead make use of the JMP Covering Array Analysis (JMP Statistical Discovery LLC, 2023) as the “state-of-the-art” approach, which has integrated such methods either in full or in part.

Returning to our `XGBoost` case study, Figure 2 shows the fault localization analysis from JMP’s Covering Array module. Similar to Ghandehari et al. (2018), this analysis first removes all combinations that have been cleared in passed cases; we call these “tested-and-passed” combinations later. The remaining combinations are then ranked in terms of its failure count, i.e., the number of failed test cases for which this combination is present. For example, the two-factor combination of `alpha = 0` and `booster = gbtree` has a failure count of 3, since it is present in three failed test runs: runs 1, 8 and 9. This ranking of potential root causes via its failure count is quite intuitive, as combinations that show up in more failed test cases should naturally be treated as more suspicious. Figure 2 shows the ranked combinations with two or three failure counts, where three is the highest count in this analysis.

Despite the intuition behind this approach, there are several notable limitations. First, such an approach is deterministic and does not provide a *probabilistic* quantification of risk that a suspicious combination is indeed a root cause. This probabilistic risk is crucial for guiding the scope of subsequent diagnosis for likely root causes. For example, in Figure 2, if we find that the combinations with three and two failure counts have 95% and near-zero root cause probabilities, respectively, then it is economically reasonable to diagnose only the former combinations and not the latter. However, if the latter two failure count combinations have 75% probability, then it is prudent to diagnose those as well for software robustness. Such decisions cannot be made with current deterministic methods. Second, in ranking combinations by failure count, the JMP analysis (and existing methods) yields many “tied” combinations, e.g., in Figure 2, there are 15 tied combinations with a failure count of two. Such ties make the subsequent diagnosis process particularly difficult, since the investigation of all 15 combinations with two failure counts is typically too costly in practice. A probabilistic ranking of combinations can alleviate this issue by disentangling

JMP Analysis for XGBoost Case Study 2

2 Factor Combinations			3 Factor Combinations		
Factors	Failure Levels	Failure Count	Factors	Failure Levels	Failure Count
alpha, booster	0, gbtree	3	max_depth, alpha, booster	6, 0, gbtree	2
booster, sample_type	gbtree, weighted	3	max_depth, booster, sample_type	9, gbtree, weighted	2
booster, normalize_type	gbtree, forest	3	max_depth, booster, normalize_type	9, gbtree, forest	2
			max_depth, sample_type, normalize_type	9, weighted, forest	2
			alpha, lambda, booster	0, 0, gbtree	2
			alpha, lambda, sample_type	0, 0, weighted	2
			alpha, learning_rate, booster	0, 0.05, gbtree	2
			alpha, learning_rate, normalize_type	0, 0.05, forest	2
			alpha, booster, sample_type	0, gbtree, weighted	2
			alpha, booster, normalize_type	0, gbtree, forest	2
			lambda, booster, sample_type	0, gbtree, weighted	2
			lambda, booster, normalize_type	1, gbtree, forest	2
			learning_rate, booster, sample_type	0.3, gbtree, weighted	2
			learning_rate, booster, normalize_type	0.05, gbtree, forest	2
			booster, sample_type, normalize_type	gbtree, weighted, forest	2

Figure 2: JMP’s Covering Array Analysis for our motivating XGBoost case study. Listed are the potential root cause combinations ranked by decreasing failure counts.

tied combinations to facilitate targeted diagnosis. Finally, existing approaches largely do not provide a framework for integrating prior domain and/or structural knowledge on root cause behavior, e.g., the aforementioned combination hierarchy and heredity principles. The integration of such knowledge can improve fault localization with limited test runs, as we shall see later.

3 The BayesFLo Model

To address these limitations, we propose a new Bayesian Fault Localization (BayesFLo) framework, which provides a principled statistical approach for assessing probabilistic risk of potential root causes via conditioning on test set outcomes. We first present the employed modeling framework, then show how it embeds the desirable structure of combination hierarchy and heredity (Lekivetz and Morgan, 2021) within its prior specification, thus enabling effective fault localization with limited (expensive) test runs.

3.1 Prior Specification

We first introduce some notation. Consider a software system (or more broadly, a complex engineering system) with $I \geq 1$ input factors, where a factor i can take on $J_i \geq 2$ different levels. A K -input combination (with $K \leq I$) is denoted as $(\mathbf{i}, \mathbf{j})_K$, where $\mathbf{i} = (i_1, \dots, i_K), i_1 < \dots < i_K$ is an ordered K -vector containing all inputs for this combination, and $\mathbf{j} = (j_1, \dots, j_K), j_k \in \{1, \dots, J_{i_k}\}$ is a K -vector indicating the levels of each corresponding input. For example, the 2-input combination of the first factor at level 1

and the second factor at level 2 can be denoted as $(\mathbf{i}, \mathbf{j})_2$, where $\mathbf{i} = (1, 2)$ and $\mathbf{j} = (1, 2)$. In the case of $K = 1$, i.e., a single input i at level j , this may be simplified to (i, j) .

Now let \mathcal{C}_K denote the set of K -input combinations $(\mathbf{i}, \mathbf{j})_K$ as described above, and let $\mathcal{C} = \cup_{K=1}^I \mathcal{C}_K$ denote the set of combinations over all orders $K = 1, \dots, I$. Further let $Z_{(\mathbf{i}, \mathbf{j})_K} \in \{0, 1\}$ be an indicator variable for whether the combination $(\mathbf{i}, \mathbf{j})_K$ is truly a root cause. As this is unknown prior to running test cases, we model each $Z_{(\mathbf{i}, \mathbf{j})_K}$ a priori as an independent Bernoulli random variable:

$$Z_{(\mathbf{i}, \mathbf{j})_K} \stackrel{\text{indep.}}{\sim} \text{Bern}\{p_{(\mathbf{i}, \mathbf{j})_K}\}, \quad (\mathbf{i}, \mathbf{j})_K \in \mathcal{C}_K, \quad K = 1, \dots, I, \quad (1)$$

where $p_{(\mathbf{i}, \mathbf{j})_K}$ is the prior probability that this combination is a root cause. Here, the view that $Z_{(\mathbf{i}, \mathbf{j})_K}$ is random makes our approach Bayesian; this contrasts with existing fault localization approaches, which presume $Z_{(\mathbf{i}, \mathbf{j})_K}$ to be fixed but unknown. For $K = 1$, this notation simplifies to $Z_{(i, j)}$ and $p_{(i, j)}$. Whenever appropriate, we denote $\mathbf{Z} = (Z_{(\mathbf{i}, \mathbf{j})_K})_{(\mathbf{i}, \mathbf{j})_K \in \mathcal{C}}$ and $\mathbf{p} = (p_{(\mathbf{i}, \mathbf{j})_K})_{(\mathbf{i}, \mathbf{j})_K \in \mathcal{C}}$ for brevity.

It is worth noting the sheer number of input combinations in \mathcal{C} that needs to be considered as potential root causes. Assuming each factor has an equal number of levels $J = J_1 = \dots = J_I$, one can show that \mathcal{C}_K contains $\binom{I}{K} J^K$ distinct combinations of order K , thus the total number of consider input combinations is $|\mathcal{C}| = \sum_{K=1}^I \binom{I}{K} J^K$. Even with a moderate number of inputs, say $I = 10$, with each having $J = 2$ levels, this amounts to $|\mathcal{C}| = 59048$ combinations. As we shall see later in Section 4, the size of \mathcal{C} forms the key bottleneck for Bayesian inference, as the computation of posterior probabilities can require $\mathcal{O}(2^{|\mathcal{C}|})$ work; this can thus be infeasible even for small software systems.

Next, we adopt the following product form on the root cause probability for $(\mathbf{i}, \mathbf{j})_K$:

$$p_{(\mathbf{i}, \mathbf{j})_K} = \prod_{k=1}^K p_{(i_k, j_k)}, \quad (\mathbf{i}, \mathbf{j})_K \in \mathcal{C}_K, \quad K = 2, \dots, I. \quad (2)$$

In words, the combination root cause probability $p_{(\mathbf{i}, \mathbf{j})_K}$ is modeled as the *product* of the root cause probabilities for its component inputs. This product form offers two advantages: it precludes the need for exhaustive prior elicitation over all combinations in \mathcal{C} (discussed later), and nicely embeds the desired principles of combination hierarchy and heredity (Lekivetz and Morgan, 2021). These principles, which capture the structured nature of

typical software root causes, can be seen as extensions of the well-known principles of effect hierarchy and heredity (Wu and Hamada, 2009), which are widely used for analysis of factorial experiments. The first principle, combination hierarchy, asserts that combinations involving fewer inputs are more likely to be failure-inducing than those involving more inputs. Empirical evidence suggests this principle holds across software across various domains (Kuhn et al., 2004). To see how our prior in (2) captures combination hierarchy, note that by its product form construction, the combination probability $p_{(\mathbf{i}, \mathbf{j})_K}$ is always less than the probability of any component input $p_{(i_k, j_k)}$. Thus, this prior assigns increasingly smaller root cause probabilities on combinations with a higher interaction order K , thus capturing the desired hierarchy structure. The second principle, combination heredity, asserts that a combination is more likely to be failure-inducing when some of its component inputs are more likely to be failure-inducing. From our product-form prior in (2), note that the combination root cause probability $p_{(\mathbf{i}, \mathbf{j})_K}$ cannot be large unless some of its component root cause probabilities in $\{p_{(i_k, j_k)}\}_{k=1}^K$ are also large. This thus captures the desired combination heredity effect. Similar product-form weights have been used for modeling hierarchy and heredity in the context of predictive modeling (Tang et al., 2023) and data reduction (Mak and Joseph, 2017).

With the product form (2), we require only the specification of the single-input root cause probabilities $\{p_{(i, j)}\}_{i, j}$. Such a specification, however, requires careful elicitation of important domain knowledge from test engineers. For most software systems at the testing stage, it may be reasonable to specify a small (i.e., near-zero) value for $p_{(i, j)}$, as this reflects the prior belief that failure-inducing root causes should occur sporadically. Oftentimes, however, an engineer has additional domain knowledge that permits a more informed prior specification. For example, the engineer may know that certain factors have been recently added to the system, and thus may be more suspicious of such factors. This heightened suspicion can be captured via a larger specification of its $p_{(i, j)}$ compared to other factors. We shall see how such domain knowledge can accelerate fault localization in later experiments.

From a Bayesian perspective, the product-form prior (2) provides a way for propagating elicited domain knowledge over the many root cause probabilities in \mathbf{p} . For example, suppose an engineer has heightened suspicions on factor i , and accordingly specifies a higher value for the single-factor root cause probabilities $\{p_{(i, j)}\}_j$. By (2), this induces larger prior root cause probabilities $p_{(\mathbf{i}, \mathbf{j})_K}$ for any combination $(\mathbf{i}, \mathbf{j})_K$ involving factor i , thus “pool-

ing” this information over such combinations. This “information pooling”, guided by the embedded principles of combination hierarchy and heredity, can facilitate the disentangling of the large number of potential root causes from limited test runs. Recent work on related notions of information pooling have shown promise in various high-dimensional inference problems, e.g., matrix completion (Yuchi et al., 2023) and multi-armed bandits (Mak et al., 2022), and we show in later experiments that this is also important for effective fault localization.

3.2 Posterior Root Cause Probabilities

In what follows, we suppress the notation $(\mathbf{i}, \mathbf{j})_K$ to (\mathbf{i}, \mathbf{j}) for brevity. Using the above prior specification, we now need to condition on the observed test case data. Suppose we run the software system at M different test cases, where the m -th test case is performed at input levels $\mathbf{t}_m = (t_{m,1}, \dots, t_{m,I})$, $t_{m,i} \in \{1, \dots, J_i\}$. Then the test data can be denoted as $\mathcal{D} = \{(\mathbf{t}_m, y_m)\}_{m=1}^M$, where $y_m \in \{0, 1\}$ is a binary variable with 1 indicating a failure and 0 if not. To make things concrete, consider the following example. Suppose the system has $I = 3$ input factors, each with two levels. Further assume there is only one true root cause $((1, 2), (1, 2))$, i.e., the combination of the first input at level 1 and the second at level 2, which results in failure. Suppose we then run the first test case at input setting $\mathbf{t}_1 = (1, 2, 1)$, i.e., with the three factors at levels 1, 2 and 1, respectively. Then, since the root cause is present in \mathbf{t}_1 , this would result in a failure, namely $y_1 = 1$. However, if we run the second test case at a different setting $\mathbf{t}_2 = (2, 2, 2)$, then this test case would result in no failure, i.e., $y_2 = 0$, as the root cause is not present in \mathbf{t}_2 . Here, we presume that observed outcomes are *deterministic*, in that the same outcome y_m is always observed whenever the software system is run with inputs \mathbf{t}_m .

With this framework, the problem of fault localization then reduces to the evaluation of the posterior root cause probabilities for *all* considered combinations in \mathcal{C} , namely:

$$\mathbb{P}(Z_{(\mathbf{i}, \mathbf{j})} = 1 | \mathcal{D}), \quad \text{for all } (\mathbf{i}, \mathbf{j}) \in \mathcal{C}. \quad (3)$$

Such a computation, however, can easily become computationally intractable. The key bottleneck lies in the complex conditioning structure from data \mathcal{D} over the high-dimensional set of combinations \mathcal{C} ; as we see later, this can then induce an $\mathcal{O}(2^{|\mathcal{C}|})$ complexity for a brute-force computation of posterior probabilities. Recall that, with the moderate setting

of $I = 10$ and $J = 2$, $|\mathcal{C}|$ consists of nearly 60000 combinations. Thus, without careful modifications to exploit problem structure, posterior computation can be intractable even for small systems!

We adopt next the following categorization of input combinations in \mathcal{C} for efficient computation of root cause probabilities:

- (a) **Tested-and-Passed (TP)**: TP combinations for a *passed* test case \mathbf{t}_m are combinations in \mathcal{C} that have been tested in \mathbf{t}_m . Continuing from the earlier example, suppose we run the test case $\mathbf{t}_m = (2, 2, 2)$ with no failure, i.e., with $y_m = 0$. Then it follows that the combination $((1, 2), (2, 2))$, i.e., with the first factor A at level 2 and the second factor B at level 2, is a TP combination. (In what follows, we may denote such a combination as A_2B_2 for notational simplicity; this should be clear from context.) For this single passed case, the set of TP combinations is $\mathcal{C}_{\text{TP},m} = \{A_2, B_2, C_2, A_2B_2, A_2C_2, B_2C_2, A_2B_2C_2\}$.
- (b) **Tested-and-Failed (TF)**: TF combinations for a *failed* test case \mathbf{t}_m are combinations in \mathcal{C} that have been tested in \mathbf{t}_m . For example, suppose we run the test case $\mathbf{t} = (1, 2, 1)$ and observe a failure, i.e., with $y_m = 1$. Then, from this single failed case, the set of TF combinations becomes $\mathcal{C}_{\text{TF},m} = \{A_1, B_2, C_1, A_1B_2, A_1C_1, B_2C_1, A_1B_2C_1\}$.
- (c) **Untested (UT)**: UT combinations are combinations in \mathcal{C} that have *not* been tested in any test case. For example, suppose we run the test case $\mathbf{t} = (1, 2, 1)$. Then one UT combination is A_2B_1 , as such a combination was not tested in \mathbf{t} .

This partition of \mathcal{C} naturally extends for multiple test runs in \mathcal{D} . Here, the TP combinations \mathcal{C}_{TP} from \mathcal{D} are the TP combinations over all *passed* test cases. The TF combinations \mathcal{C}_{TF} from \mathcal{D} are the TF combinations over all *failed* test cases, with the combinations from \mathcal{C}_{TP} removed. \mathcal{C}_{UT} then consists of all remaining combinations in \mathcal{C} . In other words:

$$\mathcal{C}_{\text{TP}} = \cup_{m:y_m=0} \mathcal{C}_{\text{TP},m}, \quad \mathcal{C}_{\text{TF}} = (\cup_{m:y_m=1} \mathcal{C}_{\text{TF},m}) \setminus \mathcal{C}_{\text{TP}}, \quad \mathcal{C}_{\text{UT}} = \mathcal{C} \setminus (\mathcal{C}_{\text{TP}} \cup \mathcal{C}_{\text{TF}}). \quad (4)$$

Figure 3 (left) visualizes this partition of \mathcal{C} from observed test runs for a simple example.

With this partition of \mathcal{C} , we now present efficient algorithms for computing the posterior root cause probabilities (3). For TP combinations, it is clear that such a combination cannot

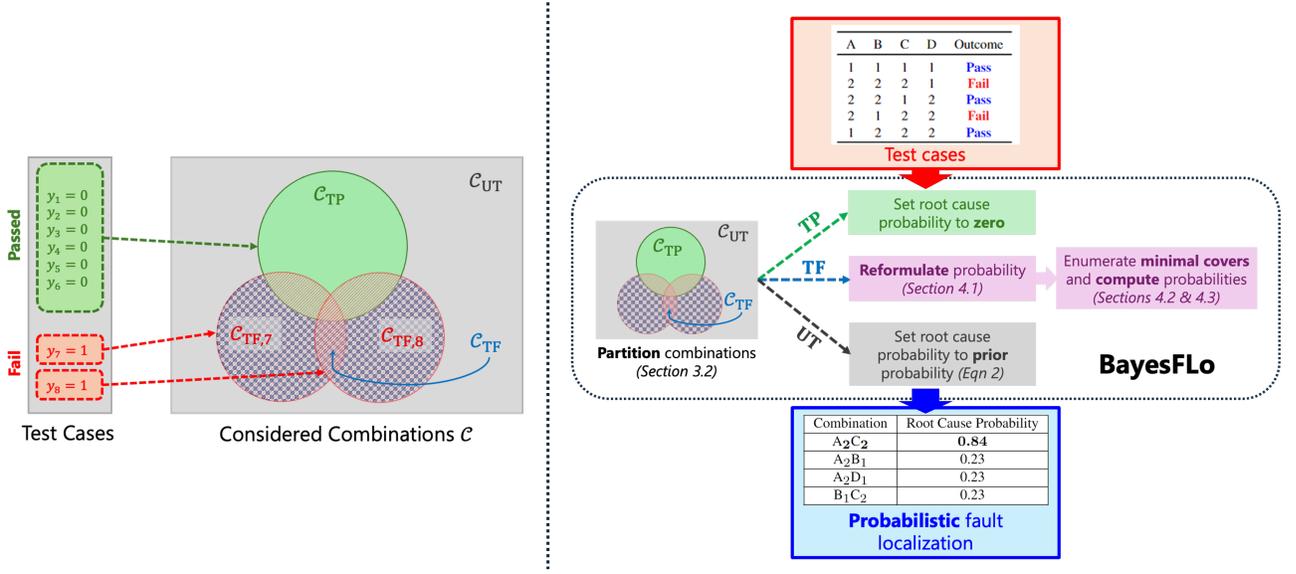


Figure 3: [Left] Visualizing the use of passed and failed test cases for partitioning the set of considered combinations \mathcal{C} into \mathcal{C}_{TP} , \mathcal{C}_{TF} and \mathcal{C}_{UT} . [Right] Workflow for the proposed BayesFlo fault localization approach.

be a root cause, as it was cleared by a passed test case. In other words:

$$\mathbb{P}(Z_{(\mathbf{i},\mathbf{j})} = 1|\mathcal{D}) = 0, \quad (\mathbf{i},\mathbf{j}) \in \mathcal{C}_{TP}. \quad (5)$$

This is akin to Ghandehari et al. (2018), which removes TP combinations from consideration for root causes. Furthermore, for UT combinations, we have:

$$\mathbb{P}(Z_{(\mathbf{i},\mathbf{j})} = 1|\mathcal{D}) = \mathbb{P}(Z_{(\mathbf{i},\mathbf{j})} = 1), \quad (\mathbf{i},\mathbf{j}) \in \mathcal{C}_{UT}, \quad (6)$$

since the observed test set \mathcal{D} does not provide any information on an untested combination (\mathbf{i},\mathbf{j}) . As such, its root cause probability given \mathcal{D} simply reduces to its prior probability given in (2). The challenge thus lies in computing posterior probabilities on the remaining class of TF combinations. We detail next an approach for computing such probabilities, leveraging tools from integer programming and graph representations. Figure 3 (right) summarizes the proposed algorithmic workflow; we elaborate on this in the following section.

4 Computation of Root Cause Probabilities

Consider the case of TF combinations, where we wish to compute the posterior root cause probability (3) for a given TF combination $(\mathbf{i}, \mathbf{j}) \in \mathcal{C}_{\text{TF}}$. One solution might be the “brute-force” approach:

$$\mathbb{P}(Z_{(\mathbf{i}, \mathbf{j})} = 1 | \mathcal{D}) = \frac{\mathbb{P}(Z_{(\mathbf{i}, \mathbf{j})} = 1, \mathcal{D})}{\mathbb{P}(\mathcal{D})} = \frac{\sum_{\mathbf{z} \in \{0,1\}^{|\mathcal{C}|}, Z_{(\mathbf{i}, \mathbf{j})} = 1} \mathbb{P}(\mathbf{Z} = \mathbf{z}) \mathbb{P}(\mathcal{D} | \mathbf{Z} = \mathbf{z})}{\sum_{\mathbf{z} \in \{0,1\}^{|\mathcal{C}|}} \mathbb{P}(\mathbf{Z} = \mathbf{z}) \mathbb{P}(\mathcal{D} | \mathbf{Z} = \mathbf{z})}. \quad (7)$$

where $\mathbb{P}(\mathbf{Z} = \mathbf{z})$ follows from Equation (2), and $\mathbb{P}(\mathcal{D} | \mathbf{Z} = \mathbf{z})$ can be deduced by reasoning. The limitation of such an approach is clear. For each $(\mathbf{i}, \mathbf{j}) \in \mathcal{C}_{\text{TF}}$, we need to compute the sum of $2^{|\mathcal{C}|-1}$ terms in the numerator and the sum of $2^{|\mathcal{C}|}$ terms in the denominator. Hence, even for small software systems with $|\mathcal{C}|$ small, this brute-force approach can be infeasible. This sheer dimensionality of potential root cause scenarios is the key bottleneck for tractable computation of probabilities for Bayesian fault localization.

To address this, we employ an alternate formulation, which allows for considerable speed-ups in computing probabilities. We first outline this reformulation, then show how this facilitates efficient computation via a connection to the related problem of minimal set covering.

4.1 An Alternate Formulation

The following proposition provides a useful reformulation of the desired posterior root cause probability for a TF combination (\mathbf{i}, \mathbf{j}) :

Proposition 1. *Let $(\mathbf{i}, \mathbf{j}) \in \mathcal{C}_{\text{TF}}$, and let:*

$$\mathcal{M}_{(\mathbf{i}, \mathbf{j})} = \{m = 1, \dots, M : y_m = 1, (\mathbf{i}, \mathbf{j}) \in \mathcal{C}_{\text{TF}, m}\} \quad (8)$$

be the index set of failed test cases for which (\mathbf{i}, \mathbf{j}) is a potential root cause. Define the event:

$$E_{(\mathbf{i}, \mathbf{j})} = \{\text{for each } m \in \mathcal{M}_{(\mathbf{i}, \mathbf{j})}, \text{ there exists some } c \in \mathcal{C}_{\text{TF}, m} \setminus \mathcal{C}_{\text{TP}} \text{ such that } Z_c = 1\}. \quad (9)$$

In words, this is the event that all failures in $\mathcal{M}_{(\mathbf{i}, \mathbf{j})}$ can be explained by the selected root causes $\{c \in \mathcal{C}_{\text{TF}} : Z_c = 1\}$. The desired posterior root cause probability then reduces to:

$$\mathbb{P}(Z_{(\mathbf{i}, \mathbf{j})} = 1 | \mathcal{D}) = \mathbb{P}(Z_{(\mathbf{i}, \mathbf{j})} = 1 | E_{(\mathbf{i}, \mathbf{j})}) = \frac{\mathbb{P}_{(\mathbf{i}, \mathbf{j})}}{\mathbb{P}(E_{(\mathbf{i}, \mathbf{j})})} \quad (10)$$

The proof of this can be found in Appendix A. There are two key advantages of this alternate form (10) over the brute-force approach (7). First, its numerator can be directly computed via Equation (2) with little work. Second, its denominator $\mathbb{P}(E_{(i,j)})$ can be effectively computed via a novel connection to a related minimal set covering problem for bipartite graphs (Asratian et al., 1998); we show this below.

To compute $\mathbb{P}(E_{(i,j)})$, we first inspect condition (9) for $E_{(i,j)}$, which requires, for each failed test case in $\mathcal{M}_{(i,j)}$, a corresponding TF combination that induces this failure. Figure 4 visualizes this condition in the form of a bipartite graph, where the left nodes are the TF combinations in \mathcal{C}_{TF} , and the right nodes are failed test cases in $\mathcal{M}_{(i,j)}$. Here, an edge is drawn from a combination c (on left) to a test case index m (on right) if $c \in \mathcal{C}_{\text{TF},m}$, i.e., if combination c is contained in the failed test inputs \mathbf{t}_m . Viewed this way, condition (9) is equivalent to finding a selection of potential root causes in $\{Z_c\}_{c \in \mathcal{C}_{\text{TF}}}$, such that every failed test case on the right is connected to (or “covered” by) a selected combination on the left via an edge. Figure 4 visualizes two possible “covers”. Such a cover of right-hand nodes can be interpreted as a selection of potential root causes (left-hand nodes) that *explain* the failed test cases. Thus, to compute the probability $\mathbb{P}(E_{(i,j)})$, we need to sum over the prior probabilities for all possible selections of potential root causes that cover the failed test cases in $\mathcal{M}_{(i,j)}$.

4.2 Enumerating Minimal Covers

With this insight, we now establish a useful link between the desired probability $\mathbb{P}(E_{(i,j)})$ and the related problem of minimal set covering. Formally, we define a *cover* of the failed test indices $\mathcal{M}_{(i,j)}$ as a subset $\tilde{\mathcal{C}}$ of the potential root causes \mathcal{C}_{TF} , such that for every $m \in \mathcal{M}_{(i,j)}$, there exists an edge connecting some node in $\tilde{\mathcal{C}}$ to m . A *minimal cover* of $\mathcal{M}_{(i,j)}$ is then a cover $\tilde{\mathcal{C}}$ of $\mathcal{M}_{(i,j)}$ which, if any element is removed from $\tilde{\mathcal{C}}$, ceases to be a cover. Figure 4 visualizes this notion of a minimal cover.

Using this definition, the following proposition reveals a useful connection:

Proposition 2. *The desired probability $\mathbb{P}(E_{(i,j)})$ can be simplified as:*

$$\mathbb{P}(E_{(i,j)}) = \mathbb{P}(\{Z_c = 1 \text{ for all } c \in \tilde{\mathcal{C}}\}, \text{ for at least one minimal cover } \tilde{\mathcal{C}} \text{ of } \mathcal{M}_{(i,j)}). \quad (11)$$

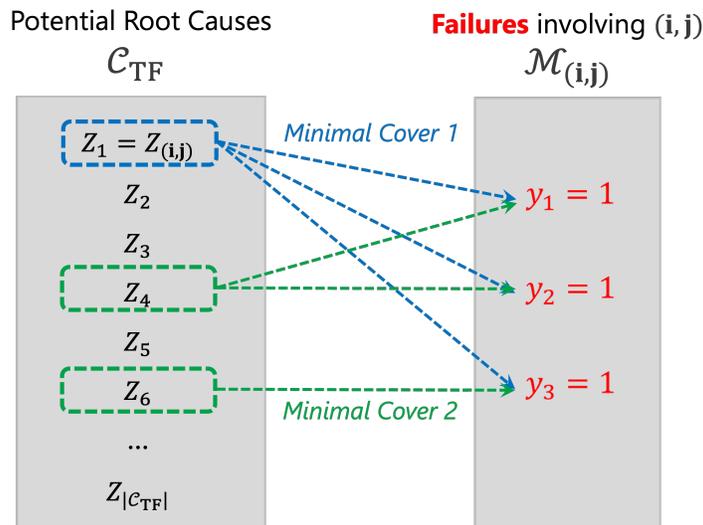


Figure 4: Visualizing the bipartite graph representation and two minimal covers for failures involving the combination (i, j) .

Its proof can be found in Appendix B. In words, this shows that $\mathbb{P}(E_{(i,j)})$ amounts to finding the probability that, for at least one minimal cover $\tilde{\mathcal{C}}$, all combinations in $\tilde{\mathcal{C}}$ are indeed root causes.

To compute (11), a natural approach is to first enumerate all minimal covers of $\mathcal{M}_{(i,j)}$. Fortunately, the set cover problem for bipartite graphs has been well-studied in the literature, and efficient polynomial-time algorithms have been developed for finding minimal covers (Skiena, 1998; Hopcroft and Karp, 1973). Leveraging such developments can thus greatly speed up the brute-force approach for posterior probability computation (see Equation (7)), which is doubly-exponential in complexity and thus infeasible for even small software systems. With recent developments in integer programming algorithms (Wolsey, 2020), a popular strategy for finding minimal set covers is to formulate and solve this problem as an integer linear program (ILP; Schrijver, 1998). We adopt such a strategy below.

Let $\mathcal{C}_{\text{TF},(i,j)}$ be the set of potential root causes in \mathcal{C}_{TF} involving $\mathcal{M}_{(i,j)}$; this is typically much smaller than \mathcal{C}_{TF} , which reduces the size of the optimization program below. We

propose the following feasibility program to find the *first* minimal cover for $\mathcal{M}_{(i,j)}$:

$$\begin{aligned}
& \arg \max 1 \quad \text{s.t.} \\
& z_c \in \{0, 1\} \text{ for all } c \in \mathcal{C}_{\text{TF},(i,j)}, \quad l_{g,m} \in \{0, 1\} \text{ for all } g \in \mathcal{C}_{\text{TF},(i,j)}, m \in \mathcal{M}_{(i,j)}, \\
\text{[C1]} \quad & \sum_{c \in \mathcal{C}_{\text{TF},(i,j)}} z_c \cdot \mathbb{I}(m \in \mathcal{M}_c) \geq 1 \text{ for all } m \in \mathcal{M}_{(i,j)}, \\
\text{[C2]} \quad & \sum_{c \in \mathcal{C}_{\text{TF},(i,j)}, c \neq g} z_c \cdot \mathbb{I}(m \in \mathcal{M}_c) \leq |\mathcal{C}_{\text{TF},(i,j)}| (1 - l_{g,m}) \text{ for all } g \in \mathcal{C}_{\text{TF},(i,j)}, m \in \mathcal{M}_{(i,j)}, \\
\text{[C3]} \quad & \sum_{m \in \mathcal{M}_{(i,j)}} l_{g,m} \geq 1 \text{ for all } g \in \mathcal{C}_{\text{TF},(i,j)}.
\end{aligned} \tag{12}$$

Here, the decision variables in this feasibility program are the binary variables $\{z_c\}$ and $\{l_{g,m}\}$, with $z_c = 1$ indicating combination c is included in the cover and $z_c = 0$ otherwise. The first constraint [C1] requires the selected combinations $\{c : z_c = 1\}$ to *cover* all failed test cases in $\mathcal{M}_{(i,j)}$. The next constraints [C2] and [C3] ensure the selected cover is indeed a *minimal* cover. To see why, note that via constraint [C2], the auxiliary indicator variable $l_{g,m} \in \{0, 1\}$ equals 1 if by removing g from the considered cover, we fail to cover failure case m . For the considered cover to be minimal, we thus need, for each g in the cover, at least one $l_{g,m} = 1$ for some failure case m ; this is ensured by constraint [C3].

One appealing property of the integer feasible program (12) is that the objective is (trivially) linear and all constraints are linear in the binary decision variables. Such an integer *linear* program thus admits nice structure for efficient large-scale optimization, particularly via recent developments in cutting plane and branch-and-bound algorithms (Balas et al., 1993; Stidsen et al., 2014). In our later implementation, we made use of the GurobiPy package in Python (Gurobi Optimization, LLC, 2023), which implements state-of-the-art optimization solvers for large-scale integer programming. Gurobi is widely used for solving large-scale optimization problems in the industry, including for the National Football League (North, 2020) and Air France (Richard, 2020). Here, with the ILP formulation (12), Gurobi can solve for a feasible minimal set cover in minutes for our later case studies. This formulation thus provides an efficient strategy for computing the desired probability $\mathbb{P}(E_{(i,j)})$.

Of course, after finding a single minimal cover via (12), we still have to find subsequent distinct minimal covers to compute (11). This can easily be performed by iteratively solving the ILP (12) with an additional constraint that ensures subsequent covers are distinct from

found covers. More concretely, let $\{\tilde{z}_c\}_{c \in \mathcal{C}_{\text{TF},(\mathbf{i},\mathbf{j})}}$ be a minimal cover found by (12). Then a subsequent cover can be found by solving the ILP (12) with the additional constraint:

$$d_c = z_c \oplus \tilde{z}_c, \quad \sum_{c \in \mathcal{C}_{\text{TF},(\mathbf{i},\mathbf{j})}} d_c \geq 1, \quad c \in \mathcal{C}_{\text{TF},(\mathbf{i},\mathbf{j})}, \quad [\text{C4}]$$

where \oplus is the XOR operator. This new constraint [C4] ensures the next cover is distinct from the previous found cover. To see why, note that d_c equals 1 only if the binary variables z_c and \tilde{z}_c are different; the inequality constraint in [C4] thus ensures all considered covers are different from the previous cover $\{\tilde{z}_c\}_{c \in \mathcal{C}_{\text{TF},(\mathbf{i},\mathbf{j})}}$. The resulting ILP is still a linear program here, as XOR can naturally be expressed as linear constraints (Magee and Glover, 1996). More specifically, the XOR condition in [C4] can be equivalently expressed as:

$$d_c \geq z_c - \tilde{z}_c, \quad d_c \geq \tilde{z}_c - z_c, \quad d_c \leq z_c + \tilde{z}_c, \quad d_c \leq 2 - z_c - \tilde{z}_c, \quad c \in \mathcal{C}_{\text{TF},(\mathbf{i},\mathbf{j})}, \quad (13)$$

which are clearly linear in the binary decision variables $\{z_c\}_{c \in \mathcal{C}_{\text{TF},(\mathbf{i},\mathbf{j})}}$.

With this, if a feasible solution is found for the ILP (12) with [C4], the optimization solver will return a distinct minimal cover, which we add to the collection. If not, the solver will instead return a “dual certificate” (Güzelsöy et al., 2010) that guarantees the ILP has no feasible solutions; such a certificate is made possible by the linear nature of the above integer program. One then iteratively solves the ILP (12) with constraint [C4] (modified to exclude two or more found covers) until the solver returns a dual certificate, in which case no feasible solutions are possible and thus all minimal covers have been enumerated.

4.3 Computing Root Cause Probabilities

After enumerating all minimal covers for $\mathcal{M}_{(\mathbf{i},\mathbf{j})}$, we can then compute the probability $\mathbb{P}(E_{(\mathbf{i},\mathbf{j})})$ via Proposition 2. Let $\mathcal{V} = \{\tilde{\mathcal{C}}_1, \dots, \tilde{\mathcal{C}}_{|\mathcal{V}|}\}$ be the collection of all minimal covers of $\mathcal{M}_{(\mathbf{i},\mathbf{j})}$ found by the above procedure. By the principle of inclusion-exclusion, it follows from (11) that:

$$\begin{aligned} \mathbb{P}(E_{(\mathbf{i},\mathbf{j})}) &= \mathbb{P}(\{Z_c = 1 \text{ for all } c \in \tilde{\mathcal{C}}\}, \text{ for at least one } \tilde{\mathcal{C}} \in \mathcal{V}) \\ &= \sum_{\text{cover } \tilde{\mathcal{C}} \in \mathcal{V}} \prod_{c \in \tilde{\mathcal{C}}} p_c - \sum_{\text{covers } \tilde{\mathcal{C}}, \tilde{\mathcal{C}}' \in \mathcal{V}} \prod_{c \in \tilde{\mathcal{C}} \cup \tilde{\mathcal{C}}'} p_c + \dots + (-1)^{|\mathcal{V}|} \prod_{c \in \tilde{\mathcal{C}}_1 \cup \dots \cup \tilde{\mathcal{C}}_{|\mathcal{V}|}} p_c, \end{aligned} \quad (14)$$

where $p_c = \mathbb{P}(Z_c = 1)$ is again the prior root cause probability of combination c . We can then plug the computed $\mathbb{P}(E_{(\mathbf{i},\mathbf{j})})$ into Equation (10) to finally compute the desired root cause probability $\mathbb{P}(Z_{(\mathbf{i},\mathbf{j})} = 1|\mathcal{D})$ for a TF combination (\mathbf{i},\mathbf{j}) .

For software systems with a small number of inputs, the set of minimal covers \mathcal{V} may not be large, in which case the computation in (14) would not be intensive. For larger systems with $|\mathcal{V}|$ large, one can employ the following second-order truncation as an approximation:

$$\mathbb{P}(E_{(\mathbf{i},\mathbf{j})}) \approx \sum_{\text{cover } \tilde{c} \in \mathcal{V}} \prod_{c \in \tilde{c}} p_c - \sum_{\text{covers } \tilde{c}, \tilde{c}' \in \mathcal{V}} \prod_{c \in \tilde{c} \cup \tilde{c}'} p_c, \quad (15)$$

which bypasses the need for computing higher-order terms involving more than two covers. Note that, by the inclusion-exclusion principle, the right-hand side of (15) *underestimates* the probability $\mathbb{P}(E_{(\mathbf{i},\mathbf{j})})$. This is by design: from (10), this then results in a slight *overestimation* of the posterior root cause probability $\mathbb{P}(Z_{(\mathbf{i},\mathbf{j})} = 1|\mathcal{D})$. From a risk perspective, this is more preferable than an approximation procedure that underestimates such probabilities.

4.4 Algorithm Summary

For completeness, we provide in Algorithm 1 a summary of the full BayesFLo procedure. Suppose a test set is performed, yielding test data $\mathcal{D} = \{(\mathbf{t}_m, y_m)\}_{m=1}^M$. Here, the test cases $\{\mathbf{t}_m\}_{m=1}^M$ should ideally be collected from a covering array to ensure good coverage of combinations, but this is not necessary for BayesFLo. With test data collected and priors elicited on the single-factor root cause probabilities $\{p_{(i,j)}\}_{i,j}$, we then partition the set of considered combinations \mathcal{C} into TP, TF and UT combinations using Equation (4). Here, if the test engineer is confident that a root cause should not exceed a certain order, then posterior probabilities need to be computed only for combinations up to such an order. This can be justified as a stronger form of combination hierarchy, and can further reduce computation for evaluating posterior probabilities.

Next, we compute posterior root cause probabilities within each category. For TP combinations, this is trivially zero as such combinations were cleared in passed cases. For UT combinations, this can be set as the prior probabilities from (2), as no information can be gleaned on such combinations from the test data. For TF combinations, its posterior probabilities can be computed via the minimal set cover approach in Section 4. Finally, with posterior probabilities computed, we can then rank the potential root causes in terms

Algorithm 1 BayesFLo: Bayesian Fault Localization

Input: Test set $\mathcal{D} = \{(\mathbf{t}_m, y_m)\}_{m=1}^M$, consisting of each test case and its corresponding test outcome.

Output: Potential root causes $(\mathbf{i}, \mathbf{j}) \in \mathcal{C}$ with posterior root cause probabilities $\mathbb{P}(Z_{(\mathbf{i}, \mathbf{j})} = 1 | \mathcal{D})$.

- 1: Elicit root cause probabilities $\{p_{(i,j)}\}_{i,j}$ from domain knowledge.
 - 2: Partition the set of considered combinations \mathcal{C} into TP, TF and UT combinations using Equation (4).
 - 3: For TP combinations, set its posterior root cause probability to 0.
 - 4: For UT combinations, set its posterior root cause probability as the prior probability (2).
 - 5: For each TF combination (\mathbf{i}, \mathbf{j}) , enumerate minimal covers for the failed cases in $\mathcal{M}_{(\mathbf{i}, \mathbf{j})}$, then compute its posterior root cause probability using Equation (15).
 - 6: Rank potential root causes (TF and UT combinations) using its corresponding posterior probabilities.
-

of their probabilities, which can be used for guiding software diagnosis; more on this later.

Figure 3 (right) visualizes the full workflow behind the BayesFLo procedure.

5 Numerical Experiments

We now explore the effectiveness of BayesFLo in a suite of experiments. We explore its performance compared to the state-of-the-art first in a simple four-factor single-root-cause experiment, then in a larger eight-factor single-root-cause experiment, and finally in a more complex eight-factor experiment with multiple root causes.

5.1 Experiment 1: Four Factors, Single Root Cause

The first experiment considers a small system with $I = 4$ factors, labeled A, B, C, D, each with $J = 2$ levels, labeled 1 and 2. Here, we select a *single* true root cause A_2C_2 , then generate $M = 5$ test runs via a strength-2 covering array. Table 3 (top left) shows the corresponding test design, which yields three passed and two failed runs. We then compare the proposed BayesFLo approach with the Covering Array Analysis module in JMP. The latter, as mentioned previously, integrates developments from existing literature, and serves as a good state-of-the-art method for comparison.

For BayesFLo, we assume little prior knowledge aside from the belief that root causes are

Test Cases & Outcomes for Experiment 1				
A	B	C	D	Outcome
1	1	1	1	0
2	2	2	1	1
2	2	1	2	0
2	1	2	2	1
1	2	2	2	0

Test Cases & Outcomes for Experiment 2								
A	B	C	D	E	F	G	H	Outcome
1	1	1	1	1	1	1	1	0
2	2	2	2	2	2	1	1	0
2	2	2	1	1	1	2	2	1
2	1	1	2	2	1	2	2	1
1	2	1	2	1	2	2	1	0
1	1	2	1	2	2	1	2	0

Test Cases & Outcomes for Experiment 3								
A	B	C	D	E	F	G	H	Outcome
1	1	1	1	1	1	1	1	0
2	2	2	2	2	2	1	1	0
2	2	2	1	1	1	2	2	0
2	1	1	2	2	1	2	2	0
1	2	1	2	1	2	2	1	1
1	1	2	1	2	2	1	2	1
2	1	2	2	1	1	2	1	1
1	2	2	2	1	2	1	1	0

Table 3: [Top left] The $M = 5$ -run test design and corresponding outcomes for Experiment 1. [Top right] The $M = 6$ -run test design and corresponding outcomes for Experiment 2. [Bottom] The $M = 8$ -run test design and corresponding outcomes for Experiment 3. Here, an outcome of 0 indicates a passed test case and 1 indicates a failed one.

sporadically occurring; as such, we set the prior single-factor root cause probabilities in (2) as $p_{(i,j)} = 0.125$ for all i and j . We further presume the test engineer is confident that there are no root causes involving all four factors, so posterior probabilities are computed only for combinations with at most three factors. Root cause probabilities are then evaluated via the proposed workflow in Figure 3 (right). Finally, these probabilities are ranked from largest to smallest to highlight important root causes for subsequent fault diagnosis.

Table 4 shows the top-ranked posterior root cause probabilities from BayesFLo for Experiment 1, and Figure 5 shows the corresponding analysis from JMP. We see that both approaches pinpoint the true root cause A_2C_2 as the most suspicious combination, which is desirable. The deterministic JMP analysis, however, does not provide a probabilistic quantification of risk for each combination. As such, it is unclear from such an analysis whether a test engineer should investigate just the top combination A_2C_2 (with two failure counts), or all 15 combinations with a single failure count. BayesFLo provides a much clearer picture of this probabilistic uncertainty. Our method yields an 85% posterior probability on A_2C_2 , which suggests this is highly likely to be a root cause. For subsequent two-factor combinations, this probability drops considerably to 23%, which suggests a reduced need for diagnosis. Here, this is the correct advice as such combinations indeed do not contain the true root cause. Finally, the three-factor combinations in our ranking have

JMP Analysis for Experiment 1

2 Factor Combinations		
Factors	Failure Levels	Failure Count
A, C	2, 2	2
A, B	2, 1	1
A, D	2, 1	1
B, C	1, 2	1
B, D	1, 2	1
B, D	2, 1	1
C, D	2, 1	1
3 Factor Combinations		
Factors	Failure Levels	Failure Count
A, B, C	2, 1, 2	1
A, B, C	2, 2, 2	1
A, B, D	2, 1, 2	1
A, B, D	2, 2, 1	1
A, C, D	2, 2, 1	1
A, C, D	2, 2, 2	1
B, C, D	1, 2, 2	1
B, C, D	2, 2, 1	1

Figure 5: JMP’s Covering Array Analysis for Experiment 1. Listed are the potential root cause combinations ranked by decreasing failure counts.

a small probability of 3%, which suggests little need for inspection (despite it having a single failure count). Such an analysis is thus much more nuanced and can better guide further diagnosis compared to existing methods.

It is worth noting that the top-ranked combinations from BayesFLo (Table 4) are all TF combinations, i.e., they appear in at least one failed test case. The UT combinations in this experiment, which all involve three factors, have a posterior root cause probability of 0.0019 from BayesFLo. This is considerably smaller than the top-ranked combinations in Table 4, which is unsurprising as the latter has appeared in at least one failed test case and should thus be treated as more suspicious. The proposed BayesFLo approach captures this intuition quantitatively via its Bayesian analysis.

5.2 Experiment 2: Eight Factors, Single Root Cause

The second experiment considers a larger system with $I = 8$ factors, each with $J = 2$ levels. Similar to before, we select a single true root cause A_2G_2 , then generate $M = 6$ test runs via a strength-2 covering array. Table 3 (top right) shows the corresponding test design, which yields four passed and two failed runs. As before, BayesFLo is compared with the JMP analysis, which serves as the state-of-the-art.

For BayesFLo, we investigate two choices of prior specifications for the root cause

BayesFLo Analysis for Experiment 1		
Combination	Posterior Probability	Failure Count
A_2C_2	0.85	2
A_2B_1	0.23	1
A_2D_1	0.23	1
B_1C_2	0.23	1
B_2D_1	0.23	1
B_1D_2	0.23	1
C_2D_1	0.23	1
$A_2B_1C_2$	0.03	1
$A_2B_2C_2$	0.03	1
$A_2B_2D_1$	0.03	1
$A_2B_1D_2$	0.03	1
$A_2C_2D_1$	0.03	1
$A_2C_2D_2$	0.03	1
$B_2C_2D_1$	0.03	1
$B_1C_2D_2$	0.03	1

Table 4: The top-ranked posterior probabilities from BayesFLo in Experiment 1, along with its corresponding failure counts.

probabilities. The first prior is similar to Experiment 1, where $p_{(i,j)} = 0.0625$ for all i and j to reflect the belief that root causes occur sporadically. The second is a more informed prior that captures domain knowledge from the test engineer. Suppose A and G were two new factors added to the software system and have not been tested previously. A test engineer may find such factors to be more suspicious a priori, and thus may assign a higher prior probability $p_{(i,j)} = 0.25$ on factors A and G, and a lower prior probability of $p_{(i,j)} = 0.0625$ for other factors. The hope is that such domain knowledge can help tease out potential root causes given limited test runs. We further suppose the engineer is confident there are no root causes involving three or more factors, so posterior probabilities are computed only for combinations with at most two factors.

Consider first the analysis with the first prior. Table 5 (top) shows the top-ranked posterior probabilities from BayesFLo using this prior, and Figure 6 shows the corresponding analysis from JMP. We see that the true root cause A_2G_2 is amongst the top-ranked combinations for both the BayesFLo and JMP analysis. But as before, the latter does not provide the desired probabilistic quantification of risk offered by BayesFLo. While the BayesFLo posterior probability for A_2G_2 is rather low at 16%, perhaps due to the small prior probability assigned, it is clear that it (along with the other five tied combinations) need to be investigated. Subsequent combinations have considerably lower probabilities, which suggests a reduced need for inspection. Such insights are thus more nuanced and can better guide further investigation by software test engineers.

Consider next the second prior, which captures domain knowledge on the elevated suspiciousness of the new factors A and G. Table 5 (bottom) shows the top-ranked probabilities for the combinations using this prior. With additional domain knowledge from this prior, we see a much higher posterior probability of 48% on A_2G_2 , which is unsurprising as this involves both new factors. This highlights two advantages of BayesFLo. First, this shows the flexibility of BayesFLo in incorporating useful domain knowledge for improving fault localization. By leveraging such information, we are able to pinpoint the true root cause A_2G_2 with much greater certainty. Second, this demonstrates the usefulness of combination heredity for disentangling the six top combinations, which were tied in the JMP analysis. With the heightened suspiciousness of factors A and G specified in the prior, this embedded heredity structure in BayesFLo then raises the prior probabilities on all combinations involving these factors, which allows our procedure to identify the true root cause with

JMP Analysis for Experiment 2

2 Factor Combinations		
Factors	Failure Levels	Failure Count
A, F	2, 1	2
A, G	2, 2	2
A, H	2, 2	2
F, G	1, 2	2
F, H	1, 2	2
G, H	2, 2	2
A, B	2, 1	1
A, C	2, 1	1
A, D	2, 1	1
A, E	2, 1	1
B, D	1, 2	1
B, D	2, 1	1
B, F	2, 1	1
B, G	1, 2	1
B, H	2, 2	1
C, E	1, 2	1
C, E	2, 1	1
C, F	2, 1	1
C, G	2, 2	1
C, H	1, 2	1
D, F	2, 1	1
D, G	1, 2	1
D, H	2, 2	1
E, F	2, 1	1
E, G	2, 2	1
E, H	1, 2	1

BayesFLo Analysis for Experiment 2 (Prior 1)		
Combination	Posterior Probability (Prior 1)	Failure Count
A ₂ G ₂	0.16	2
A ₂ F ₁	0.16	2
A ₂ H ₂	0.16	2
F ₁ G ₂	0.16	2
G ₂ H ₂	0.16	2
F ₁ H ₂	0.16	2
A ₂ B ₁	0.06	1
A ₂ C ₁	0.06	1
⋮	⋮	⋮

BayesFLo Analysis for Experiment 2 (Prior 2)		
Combination	Posterior Probability (Prior 2)	Failure Count
A ₂ G ₂	0.48	2
A ₂ F ₁	0.12	2
A ₂ H ₂	0.12	2
F ₁ G ₂	0.12	2
G ₂ H ₂	0.12	2
A ₂ B ₁	0.08	1
A ₂ C ₁	0.08	1
⋮	⋮	⋮

Figure 6: JMP’s Covering Array Analysis for Experiment 2. Listed are the potential root cause combinations ranked by decreasing failure counts. Table 5: The top-ranked posterior probabilities from BayesFLo in Experiment 2 using Prior 1 (top) and Prior 2 (bottom), along with its corresponding failure counts.

limited tests.

5.3 Experiment 3: Eight Factors, Multiple Root Causes

Finally, the third experiment investigates a system with $I = 8$ factors each with $J = 2$ levels, but with *two* true root causes B_1C_2 and G_2H_1 . Table 3 (bottom) shows the test design with $M = 8$ runs, which yields five passed and three failed runs. For BayesFLo, we employ a similar prior as Experiment 2, with $p_{(i,j)} = 0.0625$ for all i and j to reflect the belief that root causes occur sporadically. As in Experiment 2, we suppose the test engineer is confident that there are no root causes with three or more factors, thus we only compute posterior probabilities on combinations with at most two factors.

Table 6 shows the top-ranked posterior probabilities from BayesFLo for Experiment 3, and Figure 7 shows the corresponding analysis from JMP. As before, while JMP correctly identified the top two combinations as the two root causes via failure counts, it does not yield a measure of probabilistic confidence, and thus it is unclear how many further combinations (with one failure count) need to be explored to debug the software. BayesFLo

JMP Analysis for Experiment 3

2 Factor Combinations		
Factors	Failure Levels	Failure Count
B, C	1, 2	2
G, H	2, 1	2
A, E	1, 2	1
A, G	1, 2	1
A, H	1, 2	1
B, C	2, 1	1
B, F	1, 2	1
C, F	1, 2	1
D, E	1, 2	1
D, F	1, 2	1
F, G	2, 2	1
F, H	2, 2	1
G, H	1, 2	1

Figure 7: JMP’s Covering Array Analysis for Experiment 3. Listed are the potential root cause combinations ranked by decreasing failure counts.

BayesFLo Analysis for Experiment 3		
Combination	Posterior Probability	Failure Count
G ₂ H ₁	0.98	2
B ₁ C ₂	0.97	2
A ₁ G ₂	0.20	1
B ₂ C ₁	0.20	1
C ₁ F ₂	0.20	1
F ₂ G ₂	0.20	1
A ₁ E ₂	0.13	1
A ₁ H ₂	0.13	1
B ₁ F ₂	0.13	1
D ₁ E ₂	0.13	1
D ₁ F ₂	0.13	1
F ₂ H ₂	0.13	1
G ₁ H ₂	0.13	1

Table 6: The top-ranked posterior probabilities from BayesFLo in Experiment 3, along with its corresponding failure counts.

provides a more informed analysis for guiding further investigation. Its top two combinations, which are the true root causes, have a near-certain posterior probability of being a root cause. Subsequent combinations have considerably reduced posterior probabilities, and are thus much less important for investigation, as desired.

6 Fault Localization of the JMP XGBoost Interface

Finally, we return to our motivating problem on the fault localization of the XGBoost User Interface in JMP (Jones and Sall, 2011). Figure 1 shows this user interface in JMP Pro Version 17.0. As discussed in Section 2, a key challenge is the verification of software performance over the many hyperparameters that can be freely varied by users. We investigate next the effectiveness of BayesFLo in two complementary fault localization case studies for this interface.

An important consideration is in deciding what software behavior constitutes as a failure. Wong et al. (2023) defines a failure as a scenario where the system “deviates from its correct behavior”. The determination of such “correct” (or expected) behavior is known as the oracle problem in software testing (Lekivetz and Morgan, 2021). In this case, since our goal is to investigate the JMP XGBoost interface, we forgo the more tedious process of independently building a machine learning model on XGBoost for verification, and instead rely on the XGBoost Python API (Brownlee, 2016) as the “oracle” for comparison.

With this, we explore next two case studies that each investigates a different notion of

JMP XGBoost Case Study 1			
Hyperparameter	Level 1	Level 2	Level 3
max_depth	3	6	9
subsample	0.1	0.3	0.65
colsample_bytree	0.1	0.3	0.65
min_child_weight	1	5.5	10
alpha	0	1	2
lambda	0	1	2
learning_rate	0.05	0.15	0.3
iterations	20	150	300

Table 7: Considered hyperparameters (factors) for the XGBoost Case Study 1.

software failure; the first explores discrepancies in predictive performance, and the second explores discrepancies in warning messages. For the first case study, predictive performance is assessed via out-of-fold predictions from K -fold cross validation (James et al., 2013), and the discrepancy between predictions is measured via the log-relative error (LRE; see McCullough, 1998). Test outcomes with median LRE below 9.0 (as recommended in McCullough, 1998) are deemed a “failure”, and suggest a mismatch between the JMP interface and the Python oracle. After reconciling predictions, the second case study investigates discrepancies in warning messages between the two implementations; details in Section 6.2.

6.1 Case Study 1

In the first case study, we focus on testing the $I = 8$ factors from the first column of Figure 1. As such factors are continuous, we apply the equivalence partitioning strategy (Myers et al., 2004; Lekivetz and Morgan, 2021) to choose $J = 3$ discretized levels for each factor, summarized in Table 7. With this, we generate a set of $M = 15$ test runs using a strength-2 covering array. For each test case, we then compute the prediction LREs between the JMP and Python implementation to assess failures. Table 8 summarizes the test cases and its corresponding outcomes.

For BayesFLo, since we have little prior information besides the belief that root causes occur rarely, we set $p_{(i,j)} = 1/24$ for all factors i and levels j . After consulting with test engineers, it is highly unlikely that root causes in the interface involve more than two factors, thus we only compute posterior probabilities on combinations with at most two factors. Root cause probabilities are computed via the BayesFLo workflow in Figure 3 (right).

Table 9 shows the five input combinations with highest posterior root cause probabilities

Test Cases & Outcomes for JMP XGBoost Case Study 1									
max_depth	subsample	colsample_bytree	min_child_weight	alpha	lambda	learning_rate	iterations	Outcome	
6	0.3	1	5.5	0	2	0.15	20	0	
9	0.3	0.65	10	0	1	0.3	20	0	
6	0.65	0.65	10	2	2	0.05	20	0	
6	1	0.3	5.5	2	0	0.15	300	0	
9	1	1	1	0	0	0.15	150	0	
3	0.3	0.3	1	0	0	0.05	20	1	
9	1	1	10	2	2	0.3	300	0	
3	0.65	1	1	1	2	0.05	150	1	
3	1	0.65	1	2	1	0.05	300	1	
3	0.3	0.3	5.5	1	1	0.3	300	1	
3	0.3	0.3	10	2	2	0.15	150	1	
9	1	1	5.5	1	1	0.05	20	0	
9	0.65	0.3	10	1	0	0.3	150	0	
6	0.65	0.65	5.5	1	1	0.15	150	0	
6	0.65	0.65	1	0	0	0.3	300	0	

Table 8: The $M = 15$ -run test design and corresponding outcomes for the XGBoost Case Study 1. Here, an outcome of 0 indicates a passed test case and 1 indicates a failed one.

from BayesFLo. We observe that the single-factor setting `max_depth = 3` has a near-certain root cause probability of 0.999. Furthermore, the remaining four combinations all involve this setting of `max_depth = 3`, with considerably lower probabilities. This suggests that the test engineer should first investigate the JMP interface at `max_depth = 3` prior to any other combinations. Indeed, after digging into the source code, we find that `max_depth = 3` is indeed the culprit root cause, stemming from an out-of-sync issue for the default value of `max_depth` in the JMP XGBoost interface. Further inspection of the interface shows that, after this out-of-sync issue is corrected, the remaining four combinations are not root causes, which is in line with the small BayesFLo posterior probabilities from Table 9.

To contrast, the JMP analysis (which serves as the state-of-the-art) yields a more muddled picture for fault localization. Figure 8 shows a screenshot from the JMP Covering Array Analysis module, which again ranks suspicious combinations by their failure counts. We see that the top-ranked combination is `max_depth = 3` (with a failure count of 5), which is desirable as this is indeed the true root cause. After this, however, there are multiple tied combinations with three failure counts. From this deterministic analysis, it is unclear whether a test engineer should expend further budget on investigating these tied combinations, and if so, how many should be inspected. The BayesFLo probabilistic analysis clarifies such decisions for the test engineer: there is little need for further investigation beyond `max_depth = 3`, as such combinations have near-zero root cause probabilities.

JMP Analysis for XGBoost Case Study 1

1 Factor Combinations		
Factors	Failure Levels	Failure Count
max_depth	3	5
2 Factor Combinations		
Factors	Failure Levels	Failure Count
max_depth, subsample	3, 0.3	3
max_depth, colsample_bytree	3, 0.3	3
max_depth, min_child_weight	3, 1	3
max_depth, learning_rate	3, 0.05	3
subsample, colsample_bytree	0.3, 0.3	3
min_child_weight, learning_rate	1, 0.05	3

Figure 8: JMP’s Covering Array Analysis for the XGBoost Case Study 1. Listed are the potential root cause combinations ranked by decreasing failure counts.

6.2 Case Study 2

After reconciling predictive discrepancies, the second case study then investigates failures in the form of warning message discrepancies between JMP and Python for XGBoost. The inspection of such discrepancies is important for a reliable software implementation that adheres to user specifications. Here, guided by domain knowledge from JMP test engineers, we explore $I = 7$ factors, including four from Case Study 1 and three new categorical factors `booster`, `sample_type` and `normalize_type`. With this, we generate a set of $M = 12$ test runs using a strength-3 covering array. For each test case, we then investigate warning discrepancies between JMP and Python. Table 2 summarizes these test cases and its outcomes. Note that this was the motivating case study from Section 2.

For BayesFLo, our earlier analysis can be used as domain knowledge for prior elicitation in the second case study. For the three factors *not* investigated in Case Study 1, we have heightened suspicions on such factors a priori (as they were not tested previously), and thus set $p_{(i,j)} = 0.25$ for these factors. For the remaining four factors, we adopt the same $p_{(i,j)} = 1/24$ prior employed earlier, which reflects our belief that such factors are less suspicious as they have been tested in Case Study 1. After discussions with test engineers, it is highly unlikely that root causes here consists of more than three factors, so we evaluate posterior probabilities only for combinations with at most three factors.

Table 10 shows the top five combinations with highest posterior probabilities from BayesFLo. We see that the top two combinations have considerably higher probabilities above 90%, whereas subsequent combinations have much lower probabilities. This suggests

BayesFLo Analysis for JMP XGBoost Case Study 1		
Combination	Posterior Probability	Failure Count
max_depth = 3	0.999	5
max_depth = 3, alpha = 1	0.040	2
max_depth = 3, alpha = 2	0.040	2
max_depth = 3, subsample = 0.3	0.037	3
max_depth = 3, colsample_bytree = 0.3	0.037	3

Table 9: The top-ranked posterior probabilities from BayesFLo in the XGBoost Case Study 1, along with its corresponding failure counts.

BayesFLo Analysis for JMP XGBoost Case Study 2		
Combination	Posterior Probability	Failure Count
<code>booster = gbtree, sample_type = weighted</code>	0.94	3
<code>booster = gbtree, normalize_type = forest</code>	0.94	3
<code>booster = gbtree, alpha = 0</code>	0.56	3
<code>booster = gbtree, sample_type = weighted, normalize_rate = tree</code>	0.15	1
<code>booster = gbtree, sample_type = uniform, normalize_rate = forest</code>	0.15	1

Table 10: The top-ranked posterior probabilities from BayesFLo in the XGBoost Case Study 2, along with its corresponding failure counts.

that the test engineer should focus on investigating the first two combinations, with others taking much less priority. Upon inspection of the source code, we find that the first two combinations in Table 10 are indeed root causes. The root issue stems from the setting of `booster = gbtree`; from the XGBoost documentation (Chen and Guestrin, 2016), such a setting should ignore user specifications for `sample_type` and `normalize_type`. With the first two combinations in Table 10, the Python oracle returns the desired warning that `sample_type` and `normalize_type` are ignored, whereas the JMP interface fails to output this warning.

To contrast, the JMP analysis (see Figure 2 from Section 2) again yields a more opaque picture. There, we see that the top-ranked combinations are the same as that for BayesFLo, with a tied failure count of 3. Again, two such combinations are true root causes, which is desired. After this, there are however fifteen tied combinations, each with a slightly lower failure count of 2. Since such an analysis is deterministic, it is unclear whether a test engineer needs to allocate further costs for inspecting these fifteen combinations, which would be very costly! BayesFLo provides further insight via its probabilistic analysis: it suggests that the first three combinations involving `booster = gbtree` are considerably more suspicious, while remaining combinations are much less suspicious as they have near-zero root cause probabilities.

7 Conclusion

We proposed a new BayesFLo framework for Bayesian fault localization of complex software systems. Existing methods for fault localization are largely deterministic, and thus have key limitations for a probabilistic quantification of risk on potential root causes, and for integrating prior domain and/or structural knowledge from test engineers. BayesFLo

addresses such limitations via a new Bayesian model on potential root cause combinations. A key feature of this model is its embedding of combination hierarchy and heredity (Lekivetz and Morgan, 2021), which capture the structured nature of software root causes. One critical challenge is the computation of posterior root cause probabilities, which can be infeasible even for small systems. We thus developed a new algorithmic framework for computing the desired posterior probabilities, leveraging recent tools from integer programming and graph representations. We then demonstrate the effectiveness of BayesFLo over the state-of-the-art in a suite of numerical experiments, and two case studies on our motivating application of fault localization on the JMP `XGBoost` interface.

Given promising results, there are many immediate avenues for future work. One direction is the use of the BayesFLo modeling framework for sequential design of subsequent test sets. This adaptive testing of software, which can be facilitated by the proposed Bayesian model, can greatly accelerate the discovery of bugs in complex systems. Another direction is the extension of BayesFLo for fault localization of systems with continuous and mixed factors. Such a setting would be more complex, as it requires the probabilistic modeling of the fault response surface; recent work in Chen et al. (2022) appears to be useful for this goal.

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A Proof for Proposition 1

Proof: We first define the following two index sets for failed test cases:

$$\begin{aligned}\mathcal{M}_{(\mathbf{i}, \mathbf{j})} &= \{m = 1, \dots, M : y_m = 1, (\mathbf{i}, \mathbf{j}) \in \mathcal{C}_{\text{TF}, m}\}, \\ \mathcal{M}_{-(\mathbf{i}, \mathbf{j})} &= \{m = 1, \dots, M : y_m = 1, (\mathbf{i}, \mathbf{j}) \notin \mathcal{C}_{\text{TF}, m}\}.\end{aligned}$$

For a given tested-and-failed (TF) combination (\mathbf{i}, \mathbf{j}) , $\mathcal{M}_{(\mathbf{i}, \mathbf{j})}$ and $\mathcal{M}_{-(\mathbf{i}, \mathbf{j})}$ split the failed test cases into cases that either involve or do not involve (\mathbf{i}, \mathbf{j}) .

Next, we define the following events:

$$\begin{aligned}E_{\text{P}} &= \{Z_c = 0 \text{ for all } c \in \mathcal{C}_{\text{TP}}\}, \\ E_{(\mathbf{i}, \mathbf{j})} &= \{\text{for each } m \in \mathcal{M}_{(\mathbf{i}, \mathbf{j})}, \text{ there exists some } c \in \mathcal{C}_{\text{TF}, m} \setminus \mathcal{C}_{\text{TP}} \text{ such that } Z_c = 1\}, \\ E_{-(\mathbf{i}, \mathbf{j})} &= \{\text{for each } m' \in \mathcal{M}_{-(\mathbf{i}, \mathbf{j})}, \text{ there exists some } c \in \mathcal{C}_{\text{TF}, m'} \setminus \mathcal{C}_{\text{TP}} \text{ such that } Z_c = 1\}.\end{aligned}$$

Here, $E_{(\mathbf{i}, \mathbf{j})}$ is the event that all failures in $\mathcal{M}_{(\mathbf{i}, \mathbf{j})}$ can be explained by some TF combination as a root cause, and $E_{-(\mathbf{i}, \mathbf{j})}$ is the event that all failures in $\mathcal{M}_{-(\mathbf{i}, \mathbf{j})}$ can be explained by some TF combination as a root cause. Thus, the observed test data \mathcal{D} is equivalent to the intersection of the events E_{P} , $E_{(\mathbf{i}, \mathbf{j})}$ and $E_{-(\mathbf{i}, \mathbf{j})}$.

As (\mathbf{i}, \mathbf{j}) is not contained in E_{P} and $E_{-(\mathbf{i}, \mathbf{j})}$ by construction, it follows that $Z_{(\mathbf{i}, \mathbf{j})} \perp E_{\text{P}}$ and $Z_{(\mathbf{i}, \mathbf{j})} \perp E_{-(\mathbf{i}, \mathbf{j})}$. As such, the desired posterior root cause probability can be simplified as:

$$\mathbb{P}(Z_{(\mathbf{i}, \mathbf{j})} = 1 | \mathcal{D}) = \mathbb{P}(Z_{(\mathbf{i}, \mathbf{j})} = 1 | E_{(\mathbf{i}, \mathbf{j})}).$$

Next, note that $\mathbb{P}(E_{(\mathbf{i}, \mathbf{j})} | Z_{(\mathbf{i}, \mathbf{j})} = 1) = 1$ as (\mathbf{i}, \mathbf{j}) is contained in every failure case $m \in \mathcal{M}_{(\mathbf{i}, \mathbf{j})}$.

We thus get:

$$\begin{aligned}\mathbb{P}(Z_{(\mathbf{i}, \mathbf{j})} = 1 | E_{(\mathbf{i}, \mathbf{j})}) &= \frac{\mathbb{P}(Z_{(\mathbf{i}, \mathbf{j})} = 1) \cdot 1}{\mathbb{P}(E_{(\mathbf{i}, \mathbf{j})})} \\ &= \frac{p_{(\mathbf{i}, \mathbf{j})}}{\mathbb{P}(E_{(\mathbf{i}, \mathbf{j})})},\end{aligned}$$

which is as desired. □

B Proof for Proposition 2

Proof: Recall that $E_{(i,j)}$ is defined as:

$$E_{(i,j)} = \{\text{for each } m \in \mathcal{M}_{(i,j)}, \text{ there exists some } c \in \mathcal{C}_{\text{TF},m} \setminus \mathcal{C}_{\text{TP}} \text{ such that } Z_c = 1\}.$$

In words, this is the event that each failed test case in $\mathcal{M}_{(i,j)}$ can be explained by some TF combination as a root cause. Define $F_{(i,j)}$ as the event:

$$F_{(i,j)} = \{\{Z_c = 1 \text{ for all } c \in \tilde{\mathcal{C}}\}, \text{ for at least one minimal cover } \tilde{\mathcal{C}} \text{ of } \mathcal{M}_{(i,j)}\}.$$

We wish to show that $E_{(i,j)} = F_{(i,j)}$.

Consider first $E_{(i,j)} \subseteq F_{(i,j)}$. This must be true, since if we collect all TF combinations c with $Z_c = 1$ from $E_{(i,j)}$, they contain at least one minimal cover $\tilde{\mathcal{C}}$, as all failures $m \in \mathcal{M}_{(i,j)}$ are covered. This suggests that every arbitrary element in $E_{(i,j)}$ is also an element in $F_{(i,j)}$. Consider next $F_{(i,j)} \subseteq E_{(i,j)}$. This must also be true, since if we take a minimal cover $\tilde{\mathcal{C}}$ of $\mathcal{M}_{(i,j)}$ with $Z_c = 1$ for all $c \in \tilde{\mathcal{C}}$ from $F_{(i,j)}$, then for every $m \in \mathcal{M}_{(i,j)}$ there exists at least one $c \in \tilde{\mathcal{C}}$ that explains this failure. Thus every arbitrary element in $F_{(i,j)}$ is also an element in $E_{(i,j)}$. This proves the proposition. \square